

**ELECTRICAL ENGINEERING**  
School of Engineering



**EGRE 224 Introduction to Microelectronics**

**Laboratory No. 5**

**Characterization and Modeling of an NMOS Transistor**

## I. Introduction

In this laboratory you will characterize two (2) VN2222LL NMOS transistors that you will use in laboratory 6, laboratory 7, and the design project. You will use the characterization data to build a Spice model of the transistors that will also be used in these labs and the design project.

## II. Theory

The Spice model for MOS transistor is based on the equations for  $I_d$  that were discussed in class for operation in the triode and saturation region, namely:

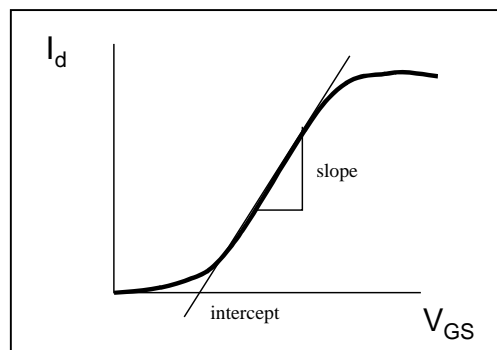
(1) Triode ( $V_{DS} < V_{GS} - V_T$ ):

$$I_D = k_n \left( \frac{W}{L} \right) \left( (V_{GS} - V_T) V_{DS} - \frac{V_{DS}^2}{2} \right)$$

(2) Saturation ( $V_{DS} \geq V_{GS} - V_T$ ):

$$I_D = k_n \left( \frac{W}{L} \right) \left( (V_{GS} - V_T)^2 (1 - \lambda V_{DS}) \right)$$

In order to develop the Spice model, we must obtain values of the parameters of  $L$ ,  $W$ ,  $V_T$ ,  $k'_n$ , and  $\lambda$ . We will take  $L$  and  $W$  for this transistor as givens and use values of  $9\mu\text{m}$  and  $13000\mu\text{m}$  respectively. Therefore, it is only left to obtain values for  $V_T$ ,  $k'_n$ , and  $\lambda$ . If we plot  $I_d$  vs.  $V_{GS}$  for an NMOS transistor for a  $V_{DS}$  of a very small value, say  $0.1\text{V}$ , we get a curve like the one below.



This region of operation is governed by (1) above. If we draw a linear approximation of this curve like the one in the graph above, it can be represented as the equation of a line:

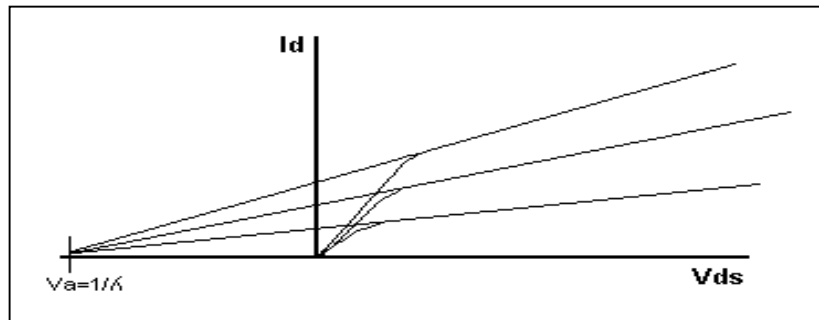
$$Y = \text{slope} \cdot (X + X_{\text{int}}) + Y_{\text{int}}$$

By comparing (1) with the equation of the line, it can be seen that for the linear segment:

$$k_n = \text{slope} / (V_{DS}(W/L)) \quad V_T = X_{\text{int}} - V_{DS}/2$$

This means that we can derive values for  $k'_n$  and  $V_T$  from the graph of  $I_d$  vs.  $V_{GS}$  for small values of  $V_{DS}$ . These values are called the low field values of  $k'_n$  and  $V_T$ , and they may be different than the values derived from the saturation characteristics, but they will be a sufficient starting point for our purposes.

Next we need to derive a value for the channel length modulation parameter,  $\lambda$ . Recall that  $\lambda$  can be derived from the graph of  $I_D$  vs.  $V_{DS}$  in the saturation region as shown below:



All we need to do is find the X intercept of the  $I_D$  vs.  $V_{DS}$  curve in saturation. This is easily done using the capabilities of the semiconductor parameter analyzer.

## II. Parameter Extraction Procedure (week 1)

Select two VN2222LL NMOS transistors from the provided supply and mark them with your lab group name and number them 1 and 2. Take good care of these transistors from now on – they are yours until the end of class! They only cost about 35¢, but if you damage or lose them, you will have to characterize their replacements!

Let one team member lead the data collection effort for the first transistor. Place the transistor into the HP16442A (Agilent 16442A) Test Fixture. The drain terminal connects to SMU1, the gate terminal connects to SMU2, and the source terminal connects to SMU3.

On the channel page, setup the SMUs as shown in the table below:

Unit	Vname	Iname	Mode	Fctn
SMU1	$V_d$	$I_d$	V	VAR2
SMU2	$V_g$	$I_g$	V	VAR1
SMU3	$V_s$	$I_s$	COMMON	CONST

On the measurement page, set VAR1,  $V_g$  to a linear sweep from 0V to 5V in 50mV steps with the compliance set to 100 $\mu$ A. Set VAR2,  $V_d$ , to a start value of 0.1V and a number of steps to 1 with a compliance of 100mA.

On the display page, set the X axis to  $V_g$  and the Y axis to  $I_d$  **for both the graphics and list display mode**, and run a single sweep. Hit the “*Scaling*” horizontal soft key and the “*Auto Scaling*” vertical softkey to expand the graph. It should look like the first example above. You may want to go back to the measurement page and increase the

start value of  $V_g$  to remove the initial portion of the graph that contains no useful information (i.e., where  $I_d=0$ ).

Now we need to add a line approximation to the graph to measure the slope and the X intercept. Make sure that the marker is turned on before going to the next step.

Begin by pressing the "Line" horizontal soft key button. The vertical soft key menu will change to Line menu. On the vertical soft key menu, hit the "Line Select None" softkey. Next find the button labeled "Line \_\_\_\_"; if the button says "Line Off" hit the button, if it says "Line On" then just continue on. Next, use the *Cursor Knob* to position the cursor to the first point of the line and hit the vertical soft key, "Cursor to Marker." Then hit the vertical soft key "Select Cursor" to chose the other cursor, move the marker to the second point of the best-fit line, and then hit the "Cursor to Marker" vertical soft key. The slope (grad) and Y intercept will be in the upper left-hand corner of the screen and the X intercept will be centered at the bottom of the screen. Record these values to use in determining your Spice model parameters.

Go back to the Graph/List page and save an ASCII version of this data on a floppy disk as you did for the diode lab. Show your graph to the instructor before you save the data.

Now we will generate a plot of  $I_d$  vs.  $V_{DS}$  for values of  $V_{GS}$  (i.e., the I-V characteristic family of curves for a MOS device). Our goal will then be to tune the Spice model of the NMOS transistor to match these curves.

Go back to the channel page and setup the SMUs as shown in the table below:

Unit	Vname	Iname	Mode	Fctn
SMU1	$V_d$	$I_d$	V	VAR1
SMU2	$V_g$	$I_g$	V	VAR2
SMU3	$V_s$	$I_s$	COMMON	CONST

On the measurement page, setup VAR1,  $V_d$ , for a sweep from 0V to 5V in 50mV steps with a compliance of 100mA. Setup VAR2,  $V_g$  for a sweep from about 0.5V under the threshold voltage measured above to 4.0V with a 500mV step and the compliance set to 100 $\mu$ A. On the display page, set the X axis to  $V_d$  **for both the graphics and list display mode** and run a single sweep. Autoscale the display. Adjust the step size for  $V_g$  on the measurement page so that the top curve just comes in below the 100mA compliance value – your goal is to obtain 4 or 5 good  $I_d$  vs.  $V_{DS}$  curves above the threshold and below the compliance value. It may help to change the start value of  $V_g$  too.

When you have an acceptable set of curves, let the instructor see them and save them on disk as before. Note that this time, you will need to keep the header information when you import the file into Excel as it tells you the values of  $V_{GS}$  for each curve!

Next, add a line, as you did above, that is parallel to the top curve. Note the value of the X intercept. This is the  $V_A$  voltage which is  $1/\lambda$ . Record this value and move the line down to the second curve. Record this value. You can use an average of these two values as your  $\lambda$  parameter. Note that  $V_A$  is fairly large, which indicates that the curves are fairly flat in the saturation region, as we would expect for a long channel device. This means that in the saturation region, the  $I_d$  vs.  $V_{GS}$  curves should be very similar for different values of  $V_{DS}$ .

To check that, go back to the channel page and set  $V_g$  as VAR1 and  $V_d$  as VAR2 as in the first step. On the measurement page, set VAR1,  $V_g$  to a sweep from just below threshold to 3.5V (use the range you found in the second step above) with a compliance of 100 $\mu$ A. Set VAR2,  $V_d$ , to a sweep from just above the threshold voltage (say 2.5V) to 5V in 200mV steps. On the display page, set the X axis back to  $V_g$  **for both the graphics and list display mode** and start the sweep. Autoscale the display and notice how all of the curves fall right on top of each other. Show the results to the instructor for verification and save them to disk as before. Note again that you must keep the header information when you import the data into Excel so that you know what value of  $V_{DS}$  each curve represents.

Now repeat the above procedure to collect data for the second transistor. Let the second lab team member lead the data collection effort for this transistor.

### III. NMOS Transistor Modeling (week 2)

As a pre-lab assignment, use the data collected for each transistor and calculate the parameters necessary to fill-out the table below:

**Table 1**

Parameter (simulation value)	Transistor 1	Transistor 2
L (on transistor symbol)	9 $\mu$ m	9 $\mu$ m
W (on transistor symbol)	13000 $\mu$ m	13000 $\mu$ m
$k'_n$ (KP)	$\mu$ A/V <sup>2</sup>	$\mu$ A/V <sup>2</sup>
$V_T$ (VTO)	V	V
$\lambda$ (LAMBDA)	V <sup>-1</sup>	V <sup>-1</sup>

Also as a pre-lab assignment, use Excel to graph your data for the three runs collected above for each transistor. In the case of the final run of  $I_D$  vs.  $V_{GS}$  for the transistor in saturation, pick a single set of data for a value of  $V_{DS}$  in the middle of the saturation region and only graph that value.

As your final pre-lab assignment fill out the table below using the data from the second run above with the values of  $I_D$  vs.  $V_{GS}$  for  $V_{DS}$  values of .5V above your saturation voltage ( $V_{DS}=V_{GS}-V_T$ ) for the largest value of  $V_{GS}$  you measured (we'll call it  $V_{GS(max)}$ ), and  $V_{DS}=4.5V$ . You will use this data to help you adjust the parameters you found above to match your simulated transistor to your measured one. Note that you may not have enough data to completely fill this table.

**Table 2**

$V_{GS}$ value (e.g. 1.8V, 2.0V, etc.)	$I_D$ value for $V_{DS}=V_{GS(max)}-V_T+0.5V$	$I_D$ value for $V_{DS}=4.5V$

When you are ready to begin the simulation, go to the class web page:

<http://www.people.vcu.edu/~rhklenke/egre224>

Click on the *Basic Schematic Capture and Analog Simulation with Design Architect and Accusim* link under the Mentor Tools item. Go through *Tutorial 4 - MOS Transistor Simulation with Accusim*. When you write the Spice file for the MOS transistor, **use the values of VT0, KP, and LAMBDA from Table 1 above for the individual transistor that you are modeling. In addition, change the values of VGS that the run is swept through to match the values of VGS that you recorded in Table 2 above.**

When you have generated the  $I_D$  vs.  $V_{DS}$  family of curves and placed the cursors on the chart as instructed (using your value of  $V_T$  to place the first cursor), compare the values of the  $I_D$  currents to the values in Table 2. Adjust the values of VT0, KP, and LAMBDA to match the simulation values to the measured values in Table 2. Note that you can edit the values of the parameters in the Spice file, save the file, and re-run the simulation without exiting Accusim - the new parameter values will be automatically read from the file when the simulation is re-run. You will have to re-generate the chart and add the cursors though.

In adjusting the parameter values, it is helpful to note that increasing the value of VT0 will shift all of the  $I_D$  curves upward, including those curves that are below the threshold voltage, and will increase the spacing between the curves as  $V_{GS}$  increases. Increasing the value of KP will simply increase the spacing of the curves above the threshold voltage. Increasing LAMBDA will increase the slope of the curves in the saturation region. A useful method to adjust parameters is to change the value of VT0 first to match the curves that are just above and just below the threshold voltage. Then adjust KP so that the upper curves match at the cursor that is placed at  $V_{DS}=V_{GS(max)}-V_T+0.5V$ . Finally, adjust the value of LAMBDA so that the curves match at the  $V_{DS}=4.5V$  cursor.

#### IV. Write-up

The write-up **can be done as a group with your lab partner**, and should include the following sections:

1. Abstract
2. Introduction
3. Theory - Show the calculations required to derive the values of  $V_T$ ,  $k'_n$ , and  $\lambda$  from the data collected in using the parameter analyzer for each transistor.
4. Results and conclusions - the write-up should include plots of your measured data for each transistor in Excel, a table listing the original calculated values for of  $V_T$ ,  $k'_n$ , and  $\lambda$  for each transistor, a table listing the adjusted values of for each transistor, and a graph of the  $I_D$  vs.  $V_{DS}$  family of curves for each transistor with both the measured and simulation data for comparison. Discuss the results in terms of the match between the measured and simulation data.